
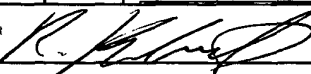


AUG 14 2002



Sheet 1 of 1

FORM PTO-1449 LIST OF REFERENCES CITED BY APPLICANT		ATTY. DOCKET NO. RUN-101-C (UM2267)		SERIAL NO. 10/092,157	
		APPLICANT Ronald M. Reano et al.			
		FILING DATE March 6, 2002		GROUP Unknown 2829	
U. S. PATENT DOCUMENT					
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS
	AA				
	AB				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)					
<i>RK</i>	AC	William Batty, Andrew J. Panks, Robert G. Johnson, and Christopher M. Snowden, <i>Fellow, IEEE</i> ; "Electrothermal Modeling and Measurement for Spatial Power Combining at Millimeter Wavelengths"; IEEE Transactions on Microwave Theory and Techniques, Vol. 47, No. 12, December 1999.			
<i>RK</i>	AD	Hector M. Gutierrez, <i>Member, IEEE</i> , Carlos E. Christoffersen, <i>Student Member, IEEE</i> , and Michael B. Steer, <i>Fellow, IEEE</i> , "An Integrated Environment for the Simulation of Electrical, Thermal and Electromagnetic Interactions in High-Performance Integrated Circuits"; in <i>IEEE 8th Elect. Performance Electron. Packag. Topical Meeting</i> , Oct. 1999, pp. 217-220			
<i>RK</i>	AE	R.G. Johnson, C.M. Snowden, and R.D. Pollard, "A Physics-Based Electro-Thermal Model for Microwave and Millimeter Wave HEMTs," <i>IEEE MTT-S Int. Microwave Symp. Dig.</i> , vol. 3, June 1997, pp. 1485-1488			
<i>RK</i>	AF	N.S. Cheng, P. Jia, D.B. Rensch, and R.A. York, "A 120-W X-band Spatially Combined Solid-State Amplifier," <i>IEEE Trans. Microwave Theory Tech.</i> , vol. 47, pp. 2557-2561, Dec. 1999			
<i>RK</i>	AG	J. Hubert, L. Mirth, S. Ortiz, and A. Mortazawi, "A 4-watt Ka-band Quasi-Optical Amplifier," <i>IEEE MTT-S Int. Microwave Symp. Dig.</i> , vol. 2, June 1999, pp. 551-554			
<i>RK</i>	AH	Y.P. Varshni, "Temperature Dependence of the Energy Gap in Semiconductors," <i>Physica</i> , vol. 34, pp. 149-154, May 1967			
<i>RK</i>	AI	H.D. Casey, D.D. Sell, and K.W. Wecht, "Concentration Dependence of the Absorption Coefficient for n- and p-type GaAs Between 1.3 and 1.6 eV," <i>J. Appl. Phys.</i> , vol. 46, pp. 250-257, Jan 1975			
<i>RK</i>	AJ	M. Shinagawa and T. Nagatsuma, "Electro-optic Sampling Using an External GaAs Probe Tip," <i>Electron. Lett.</i> , vol. 26, pp. 1341-1343, Aug. 1990			
<i>RK</i>	AK	D. Conn, X.Wu, J. Song, and K. Nickerson, "A Full Wave Simulation of Disturbances in Picosecond Signals by Electro-optic Probing," <i>IEEE MTT-S Int. Microwave Symp. Dig.</i> New York, June 1992, pp. 665-668			
<i>RK</i>	AL	X. Wu, D. Conn, J. Song, and K. Nickerson, "Invasiveness of LiTaO ₃ and GaAs Probes in External E-O Sampling," <i>J. Lightwave Technol.</i> , vol. 11, pp. 448-454, Mar. 1993			
<i>XK</i>	AM	M.Y. Frankel, J.F. Whitaker, G.A. Mourou, and A. Valdmanis, "Experimental Characterization of External Electrooptic Probes," <i>IEEE Microwave Guided Wave Lett.</i> , vol. 1, pp. 60-62, Mar. 1991			
<i>RK</i>	AN	G. Liang, Y. Liu, and K. Mei, "Full-Wave Analysis of Coplanar Wave-Guide and Slotline Using the Time-Domain Finite-Difference Method," <i>IEEE Trans. Microwave Theory Tech.</i> , vol. 37, pp. 1949-1957, Dec. 1989			
EXAMINER <i>[Signature]</i>		DATE CONSIDERED 3-10-03			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not considered. Include a copy of this form with next communication to applicant.					

part of paper #4

FORM PTO-1449 LIST OF REFERENCES CITED BY APPLICANT				ATTY. DOCKET NO. RUN-101-C		SERIAL NO. 10/092,157	
				APPLICANT Whitaker et al.			
				FILING DATE March 6, 2002		GROUP 2829	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS	PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE	
RK	AA	5,412,330	5/2/1995	Ravel et al.	324	753	6/16/1993
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
	DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
	AB						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
RK	AC	Yang, K. et al.; "High-Resolution Electro-Optic Mapping of Near-Field Distributions in Integrated Microwave Circuits"; IEEE MTT-S Digest (1998) p. 949 - 952. (Month Unavailable)					
RK	AD	David, G. et al.; "Electro-Optic Mapping of Guided and Radiated Electric Fields from Microwave Integrated Circuits and Antennas"; CLEO '98, Post-Deadline Paper (May 1998) p. 1,2.					
RK	AE	David, G. et al.; "3D Near-Field Analysis of a 4X4 Grid Oscillator Using an Electro-Optic Field Imaging System"; 28th European Microwave Conference (October 5 - 9, 1998) p. 1 - 6					
RK	AF	David, G. et al.; "Electro-Optic Imaging of Millimeter-Wave Field Distributions"; Lasers and Electro-Optics Society Annual Meeting (LEOS '98) (December 1998) p. 1,2					
RK	AG	Yang, K. et al.; "Electro-Optic Field Mapping of Quasi-Optic Power-Combining Arrays"; 1999 Ultrafast Electronics and Optoelectronics Conference (April 1999) p. 1 - 4					
RK	AH	Yang, K. et al.; "Far-Field Analysis of a Ka-Band Patch Antenna Array Using High-Resolution Electro-Optic Near Field Mapping"; 2000 European Microwave Conference (2000) p. 1 - 3 (Month Unavailable)					
RK	AI	Yang, K. et al.; "Microwave-Field Imaging with a Fiber-Based Electro-Optic Probe"; LEOS 2000 (November 2000) p. 1 - 3					
RK	AJ	Yang, K. et al.; "Fiber-Based Electro-Optic Field Imaging System"; 2001 Ultrafast Electronics and Optoelectronics Conference (2001) p. 1 - 3 (Month Unavailable)					
RK	AK	Yang, K. et al.; "Electrooptic Mapping of Near-Field Distributions in Integrated Microwave Circuits"; IEEE Transactions on Microwave Theory and Techniques; Vol. 46, No. 12 (December 1998) p. 2338 - 2343					
RK	AL	Yang, K. et al.; "Electrooptic mapping and Finite-Element Modeling of the Near-Field Pattern of a Microstrip Patch Antenna"; IEEE Transactions on Microwave Theory and Techniques; Vol. 48, No. 2 (February 2000) p. 288-294					
RK	AM	Yang, K. et al.; "Electro-optic field mapping system utilizing external gallium arsenide probes"; Applied Physics Letters; Vol. 77, No. 4 (July 2000) p. 486 - 488					
RK	AN	Yang, K. et al.; "Electric Field Mapping System Using an Optical-Fiber-Based Electrooptic Probe"; IEEE Microwave and Wireless Components Letters; Vol. 11, No. 4 (April 2001) p. 164 - 166					
EXAMINER 				DATE CONSIDERED 3-10-03			
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part of paper #6

FORM PTO-1449 LIST OF REFERENCES CITED BY APPLICANT				ATTY. DOCKET NO. RUN-101-C		SERIAL NO. 10/092,157	
				APPLICANT Whitaker et al.			
				FILING DATE March 6, 2002		GROUP 2829	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE
RK	AO	5,952,818	9/14/1999	Zhang et al.	324	96	10/25/1996
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
RK	AQ	Yang, K. et al.; "Active-Amplifier-Array Diagnostics Using High-Resolution Electrooptic Field Mapping"; IEEE Transactions on Microwave Theory and Techniques; Vol. 11 No. 4 (May 2001) p. 849 - 857					
RK	AR	Valdmanis, J. et al.; "Subpicosecond Electrooptic Sampling: Principles and Applications"; IEEE Journal of Quantum Electronics; Vol. QE-22, No. 1 (1986) ^{January 1986} p. 69 - 78					
RK	AS	Heutmaker, M.S. et al.; "Electrooptic Sampling of a Packaged High-Speed GaAs Integrated Circuit"; IEEE Journal of Quantum Electronics; Vol. 24, No. 2 (1988) ^{February 1988} p. 226 - 233					
RK	AT	Nagatsuma, T. et al.; "Subpicosecond sampling using a noncontact electro-optic probe"; J. Appl. Phys.; Vol. 66, No. 9 (1990) ^{November 1989} p. 4001 - 4009					
RK	AU	Hjelme, D. et al.; "Voltage Calibration of the Direct Electrooptic Sampling Technique"; IEEE Transactions on Microwave Theory and Techniques; Vol. 40, No. 10 (1992) ^{October 1992} p. 1941 - 1950					
RK	AV	Song, J. et al.; "An Equivalent Circuit Model of the Optical Probe in Electro-Optical Sampling Systems"; Microwave and Optical Technology Letters; Vol. 6, No. 8 (1993) ^{June 1993} p. 493 - 498					
RK	AW	Thomann, W. et al.; "Optimization of Electrooptic Sampling by Volume-Integral Method"; IEEE Transactions on Microwave Theory and Techniques; Vol. 41, No. 12 (1993) ^{December 1993} p. 2392 - 2399					
RK	AX	Pfeifer, T. et al.; "Optoelectronic On-Chip Characterization of Ultrafast Electric Devices: Measurement Techniques and Applications"; IEEE Journal of Selected Topics in Quantum Electronics; Vol. 2, No. 3 (1996) ^{September 1996} p. 586 - 604					
RK	AY	Pfeifer, T. et al.; "Three-dimensional experimental analysis of the near-field and far-field radiation of planar millimeter-wave transmitters"; OSA Trends in Optics and Photonic Sensors (TOPS); Vol 13 ^(Date Unavailable)					
RK	AZ	Pfeifer, T. et al.; "Electro-Optic Near-Field Mapping of Planar Resonators"; IEEE Transactions on Antennas and Propagation; Vol. 46, No. 2 (1998) ^{February 1998} p. 284 - 291					
RK	BA	Mueller, P. et al.; "New Calibration Method in Electrooptic Probing Due to Wavelength Control and Fabry-Perot Resonance"; IEEE Transactions on Microwave Theory and Techniques; Vol. 47, No. 3 (1999) ^{March 1999} 308-314					
RK	BB	Cecelja, F. et al.; "Electrooptic Sensor for Near-Field Measurement"; IEEE Transactions on Instrumentation and Measurement; Vol. 48, No. 2 (1999) ^{April 1999} p. 650 - 653					
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				APPLICANT Whitaker et al.			
				FILING DATE March 6, 2002		GROUP 2829	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE
RK	BC	5,772,325	6/30/1998	Hopson et al.	374	753	
RK	BD	5,713,667	2/3/1998	Alvis et al.	374	178	
RK	BE	6,297,650	10/2/2001	Ito et al.	324	753	
RK	BF	5,725,308	3/10/1998	Smith et al.	374	169	
RK	BG	5,592,101	1/7/1997	Takahashi et al.	324	753	
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
	BD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
RK	BE	Wakana, S. et al.; "Novel Electromagnetic Field Probe Using Electro/Magneto-Optical Crystals Mounted on (Month Unavailable) Optical Fiber Facets For Microwave Circuit Diagnosis"; IEEE MITT-S Digest (2000) p. 1615 - 1618					
RK	BF	Wakana, S. et al.; "Fiber-Edge Electrooptic/Magneto optic Probe for Spectral-Domain Analysis of (December 2000) Electromagnetic Field"; IEEE Transactions on Microwave Theory and Techniques; Vol 48, No. 12 (2000) p. 2611 - 2616					
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				APPLICANT Whitaker et al.			
				FILING DATE March 6, 2001		GROUP 2829	
U. S. PATENT DOCUMENT							
EXAMINER INITIALS		PATENT NO.	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE
<i>RK</i>	AA	5,459,394	10/17/1995	De Kort et al.	324	96	
<i>RK</i>	AB	5,278,499	1/11/1994	Ito et al.	324	244.1	
<i>RK</i>	AC	5,111,135	5/5/1992	Kozuka et al.	324	96	
<i>RK</i>	AD	4,928,058	5/22/1990	Williamson	324	96	
<i>RK</i>	AE	4,737,775	4/12/1988	Tokuda et al.	340	647	
	AF						
	AG						
	AH						
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	AK						
FOREIGN PATENT OR PUBLISHED PATENT APPLICATION							
		DOCUMENT NO.	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION
<i>RK</i>	AL	GB 2343964	5/24/2000	United Kingdom	—	—	
<i>RK</i>	AM	63-151867		Japan	—	—	No
<i>RK</i>	AN	WO 97/45747	12/4/1997	PCT	—	—	
<i>RK</i>	AO	WO 99/41619	8/19/1999	PCT	—	—	
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
	AR						
	AS						
	AT						
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